

SHEET 1 OF 1

Form PTO 1449		U.S. DEPARTMENT OF	COMMERCE	ATTY DOCKET NO.	SERIAL NO. New Divisional Application				
(Modified)		PATENT AND TRADEM	ARK OFFICE	219527US2S DIV					
LIST OF	REEE	RENCES CITED BY ADDI	CANT	APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT				50,000,000	000110				
				FILING DATE		GROUP			
				Herewith		<u> </u>			
		γ		U.S. PATENT DOCUMENTS		,			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	SUB CLASS	CLASS IF APPROPRIATE			
HW	AA	5,687,160	11/97	Aotake et al.		_			
BW	AB	5,731,852	03/98	Lee					
M	AC	6,185,365	02/01	Murase et al.					
bu-	AD	6,067,400	05/00	Saeki et al.			P T o		
	AE								
	AF						.s 762		
	AG						7007		
	АН						SQ = 8		
, 	Al						11 f		
	AJ								
	AK		-						
	AL								
	АМ								
	AN								
			FO	REIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY		YES	TRANSLATION NO		
ba/	AO	7-143429	06-02-95	JAPAN			X		
	AP								
	AQ								
	AR								
	AS								
	AT								
	AU								
	AV								
		OTHER REFE	RENCES (Including Author, Title, Date, Pertiner	nt Pages, et	tc.)			
	AW								
	AX				***		-		
	AY					- 17			
	AZ				Addit	tional Refe	rences sheet(s) attached		
Examiner	- FU 1000 / EN					Date Considered 4/18/03			
*Examiner: In	itial if re	eference is considered, wh	ether or not	citation is in conformance with MPEP 6	09; Draw lir	ne through	citation if not in		

Form PTO 1449 (Modified)	.,	" U.S. DEPARTMENT PATENT AND TRAD	OF COMMERCE DEMARK OFFICE	ATTY DOCKET NO. 219527US-2S DIV			SERIAL NO. 10/076,277		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO et al.					
				FILING DATE February 19, 2002			GROUP 2615		
	7			J.S. PATENT DOCUM	MENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAM	E	CLASS	SUB FILING DATE CLASS IF APPROPRIATE		
Hu,	ĀĀ	5,712,947	27 Jan 1998	Oguro et al.)		
184/	AB	6,148,138	14 Nov 2000	Sawabe et al.					
	AC								
	AD								
	AE								
	AF						l 		
	AG								
	AH								
	Al						<u> </u>		
	AJ								
	AK								
	AL				····				
	AM								
	AN								
			L			L	<u> </u>		
		1	FO	REIGN PATENT DOC	UMENTS				
		DOCUMENT NUMBER	DATE	COUNTRY			TRANSLATION YES NO		
the	AO	JP 5-158778	25 Jun 1993	Japan			x		
In.	AP	JP 5-165935	2 July 1993	Japan			x		
in.	AQ	JP 7-143429	2 Jun 1995	Japan (with Stateme	nt of Relevancy)				. x
w.	AR	JP 8-205014	9 Aug 1996	Japan			х		
Bu	AS	JP 9-182013	11 July 1997	Japan			x		_
w	ΑT	JP 11-136613	21 May 1999	Japan			х		
	ΑU								
	AV								
		OTHER RI	EFERENCES (ncluding Author, Tit	le, Date, Pertinent	Pages, e	tc.)		
Br.	AW	Explanation-of-Circum English-Translation).	stances Conce	rning-Accelerated-Exa	mination for Japan	ese-Pater	rt-Applicatik	e n No. /	∆ D0 0201476 (w ith
bu.	AX	Explanation=of-Circumstances-Concerning-Accelerated Examination=for_Japanese-Patent-Application-NoAD09804370-(with English-Translation).							
lon	AY	Explanation of Circumstances Concerning Accelerated Examination for Japanese Patent Application No AD09904199 (with English Franslation).							
	AZ				,,,,,				
Examiner		HUY NG	COYFA			Date Cor	ısidered	4	118/03
*Examiner: Ini	tial if re	eference is considered,			ance with MPEP 60)9; Draw li	ne through	citation	
conformance	and no	t considered Include of	any of this form	with payt communica	tion to applicant		•		

Form PTO 1449 (Modified)	49 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 219527US2S DIV			SERIAL NO. 10/076,277		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al					
				FILING DATE 02/19/02			GROUP 2615		
	U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUB FILING DATE CLASS IF APPROPRIAT		
the	AA	6,385,389	7 May 2002	Maruyama et al.		_			
	AB	PE	\					RE	CEIVED
	AC	10	20					OCT	
	AD	OCT 0 9 2002	OFFICE					007	1 0 2002
	AE		10,				Tec	chnology Center 260	
	AF	WENT & INADEN	7					03 ochiter 260	
		a Inn	FO	REIGN PATENT I	OCUMENTS				
		DOCUMENT NUMBER	DATE		COUNTRY		TRANSLATION YES NO		SLATION NO
th	AG	EP 1 065 665 A1	03 Jan 2001	EPO (In English)					-
th	АН	JP 5-81787	2 Apr 1993	JAPAN			х		
In	Al	JP 8-106721	23 Apr 1996	JAPAN			X		
Wil	AJ	JP 9-259539	3 Oct 1997	JAPAN			Х		
low	AK	JP 11-215471	6 Aug 1999	JAPAN					X
1/1/	/AL	JP 11-238362	31 Aug 1999	JAPAN					X
	AM								, · · ·
	AN								
	AO				, , , , , , , , , , , , , , , , , , ,				
	AP						ļ		
	AQ								
	AR								
		OTHER RI	EFERENCES (Including Author	, Title, Date, Pertine	ent Pages, e	etc.)		
BN	Evaluation of Generalization Accelerated Evamination for typensor Patent Application No. 2001-310033								
WW	AT	Explanation-of-Gircumstances-Concerning-Accelerated Examination-for-Japanese Patent Application. No2001-310034 (with English-Translation).							
low	AU	Explanation-of-Gircumstances Concerning-Accelerated-Examination for Japanese-Patent-Application No 2001-310035 (with English-Translation).							
1st	ΑV	Explanation-of-Gircumstances Concerning Accelerated Examination-for-Japanese Patent-Application: No.=2001-310036 (with-English-Translation).							
low	AW	Explanation:of-Gircumstances-Goncerning-Accelerated-Examination:for-Japanese-Patent?Application:No:-2004-310037 (with-English-Translation).							
	AX								
	AY				•				
	AZ								
Examiner		HUY NOU	YEU			Date Co	nsidered	4/1	8/03
*Examiner: In	itial if r	eference is considered, of considered. Include c	whether or not	citation is in conf	ormance with MPEP	609; Draw I	ine through	citation	n if not in